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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10008408	11/13/2001	714	738	2133	KERERO

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RSD

**CONTINUING DATA VERIFIED: NO
JL 4/2/04

** FOREIGN APPLICATIONS VERIFIED: NO
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PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed 35 USC 119 conditions met		<input type="checkbox"/> yes <input checked="" type="checkbox"/> no <input type="checkbox"/> yes <input checked="" type="checkbox"/> no
ATTORNEY DOCKET NO Verified and Acknowledged Examiners's initials ADTST.037AUS		
TITLE : Event based test system having improved semiconductor characterization map U.S.DEP'T OF COMM./PAT. & TM-PTO-436L(Rev. 12-94)		

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G.
ISSUE FEE		DRAWING		
Amount Due	Date Paid	Sheets Drwg.	Figs.Drwg.	Print Fig.
<input type="checkbox"/> TERMINAL DISCLAIMER		Primary Examiner		
		PREPARED FOR ISSUE		Application Examiner
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